Date Searched: 3/22/2006
Databases Searched: USPAT, USPGPUB
Plurals: ON
Terms Searched:
L1   (programmable adj3 (device or array)) or fpga or pga or pld or cpld
L2   (gate near5 leak$4)
L3   (power or current or voltage) same (consumption or dissipat$4 or consum$2 or leak$4)
L4   2 same 3
L5   1 and 4
Results: 385 hits
L6   716/1-18.ccls. and 5 and @pd>20060218
Results: 0 hit

Date Searched: 2/18/2006
Databases Searched: USPAT, USPGPUB
Plurals: ON
Terms Searched:
L1   (programmable adj3 (device or array)) or fpga or pga or pld or cpld
L2   (gate near5 leak$4)
L3   (power or current or voltage) same (consumption or dissipat$4 or consum$2 or leak$4)
L4   2 same 3
L5   1 and 4
Results: 385 hits
L6   716/1-18.ccls. and 5 and @pd>20051223
Results: 1 hit

US 6993737 B1   USPAT Anderson; Jason H. et al.   716/5

Date Searched: 12/23/2005
Databases Searched: USPAT, USPGPUB
Plurals: ON
Terms Searched:
L1   (programmable adj3 (device or array)) or fpga or pga or pld or cpld
L2   (gate near5 leak$4)
L3   (power or current or voltage) same (consumption or dissipat$4 or consum$2 or leak$4)
L4   2 same 3
L5   1 and 4
Results: 385 hits
L6   716/1-18.ccls. and 5
Results: 6 hits

L7   (power or current or voltage) near5 (dissipat$4 or leak$4)
L8   1 and 7 and 716/1-18.ccls.
Results: 169 hits
L9   (gate or gated or gating) same 7
L10   8 and 9
Results: 65 hits
L11   stack$3 near3 transistor
L12   10 and 11
Results: 0 hit
L13   (statistic$2 or probability or likelihood or likely) same (low or high or on or off or active or inactive or enable$1 or disable$1)
L14   13 same 7
L15   1 and 9 and 14

Results: 35 hits

L16   1 and 9 and 11
Results: 110 hits
L17   16 and 716/1-18.ccls.
Results: 0 hit
L18   (statistic$2 or probability or likelihood or likely) same stack$3
L19   1 and 9 and 18
Results: 22 hits
L20   1 and (9 same 11)
Results: 3 hits

US 20040216074 A1   US-PGPUB   Hart, Michael J. et al.   716/16
US 6324678 B1   USPAT Dangelo; Carlos et al.   716/18
US 6038386 A   USPAT Jain; Gitu   716/16
US 5712790 A   USPAT Ditlow; Gary Stephen et al.   716/2
US 6345379 B1   USPAT Khouja; Adel et al.   716/4

US 20050091629 A1   US-PGPUB   Eisenstadt, Robert et al.716/13
US 6075932 A   USPAT Khouja; Adel et al.   716/4
US 20050097496 A1   US-PGPUB   Koike, Hanpei et al.   716/13
US 20040025135 A1   US-PGPUB   Hart, Michael J. et al.   716/16
US 6777978 B2   USPAT Hart; Michael J. et al.   326/38
US 6681376 B1   USPAT Balasinski; Artur et al.   716/4
US 6289488 B1   USPAT Dave; Bharat P. et al.   716/1
US 6230303 B1   USPAT Dave; Bharat P.716/7

US 6562638 B1   USPAT Balasinski; Artur et al.   438/14
US 20050198606 A1   US-PGPUB   Gupta, Sanjay et al.   716/18
US 20050071800 A1   US-PGPUB   Liu, Ming-Kang 716/18
US 20040250231 A1   US-PGPUB   Killian, Earl A. et al.   716/18
US 20030208733 A1   US-PGPUB   Sokolov, Serguei A.   716/4
US 6871172 B1   USPAT Sanders; Lester 703/14
US 6480815 B1   USPAT Olson; Janet et al.   703/14
US 6195630 B1   USPAT Mauskar; Ashutosh S. et al.   703/18
US 5949689 A   USPAT Olson; Janet et al.   703/14
US 5508939 A   USPAT Kim; Jaeseok et al.   716/7

Stacked transistors
US 5694055 A   USPAT Shimanek; Schuyler E.   326/37
US 6868014 B1   USPAT Melik-Martirosian; Ashot et al.   365/185.28

Databases Searched: EPO, JPO, IBM TDB, Derwent
Plurals: ON
Terms Searched:
L1   (programmable adj3 (device or array)) or fpga or pga or pld or cpld
L2   (power or current or voltage) near5 (dissipat$4 or leak$4)
L3   (gate or gated or gating) same 2
L4   1 and 3
Results: 31 hits
L5   stack$3 near3 transistor
L6   4 and 5
Results: 1 hit
L7   (statistic$2 or probability or likelihood or likely) same stack$3
L8   1 and 3 and 7
Results: 1 hit

L9   (statistic$2 or probability or likelihood or likely) same (low or high or on or off or active or inactive or enable$1 or disable$1)
L10   1 and 3 and 9
Results: hits

EP 416903 A2 A2, A3 EPO   WHITTEN, RALPH G et al.
NN9603163   IBM_TDB
NN8803247   IBM_TDB
US 6871172 B   DERWENT   SANDERS, L
US 6768338 B   DERWENT   KONDAPALLI, V M et al.
US 5576636 A   DERWENT   BAUCOM, T L
EP 667679 A A1, B1 DERWENT   HANWOOD, M G
NN940169   IBM_TDB

Database Searched: IEE/IEEE XPlore
Terms Searched: ((programmable <near/3> (device or array)) or fpga or pga or pld or cpld) and
((power or current or voltage) <near/5> (dissipat* or leak*)) and (gate or gated or gating)

Results: Your search matched **89** of **1286976** documents.

Terms Searched: ((programmable <near/3> (device or array)) or fpga or pga or pld or cpld) and
((power or current or voltage) <near/5> (dissipat* or leak*)) and (gate or gated or gating) and (stack* <near/5> transistor)

Results: Your search matched **1** of **1286976** documents.

Terms Searched: ((programmable <near/3> (device or array)) or fpga or pga or pld or cpld) and
((power or current or voltage) <near/5> (dissipat* or leak*)) and (statistic* or probability or likelihood or likely) and stack*

Results: Your search matched **0** documents.

Terms Searched: ((programmable <near/3> (device or array)) or fpga or pga or pld or cpld) and
((power or current or voltage) <near/5> (dissipat* or leak*)) and ((statistic* or probability or likelihood or likely) <near/15> (low or high or on or off or active or inactive or enable* or disable*))

Results: Your search matched **4** of **1286976** documents.